

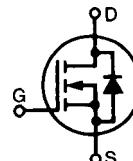
HiPerFET™ Power MOSFETs

**IXFH/IXFM11N80
IXFH/IXFM13N80**

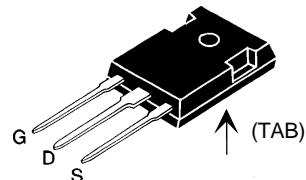
N-Channel Enhancement Mode
High dv/dt, Low t_{rr} , HDMOS™ Family

V_{DSS}	I_{D25}	$R_{DS(on)}$
800 V	11 A	0.95 Ω
800 V	13 A	0.80 Ω

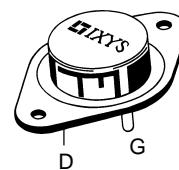
$t_{rr} \leq 250 \text{ ns}$



TO-247 AD (IXFH)



TO-204 AA (IXFM)



G = Gate,
S = Source,
TAB = Drain

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	800	V	
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	800	V	
V_{GS}	Continuous	± 20	V	
V_{GSM}	Transient	± 30	V	
I_{D25}	$T_c = 25^\circ\text{C}$	11N80 13N80	11 13	A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	11N80 13N80	44 52	A
I_{AR}	$T_c = 25^\circ\text{C}$	11N80 13N80	11 13	A
E_{AR}	$T_c = 25^\circ\text{C}$	30	mJ	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$	5	V/ns	
P_D	$T_c = 25^\circ\text{C}$	300	W	
T_J		-55 ... +150	$^\circ\text{C}$	
T_{JM}		150	$^\circ\text{C}$	
T_{stg}		-55 ... +150	$^\circ\text{C}$	
T_L	1.6 mm (0.062 in.) from case for 10 s	300	$^\circ\text{C}$	
M_d	Mounting torque	1.13/10	Nm/lb.in.	
Weight		TO-204 = 18 g, TO-247 = 6 g		

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 3 \text{ mA}$	800		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 \text{ mA}$	2.0	4.5	V
I_{GSS}	$V_{GS} = \pm 20 \text{ V}$, $V_{DC} = 0$		± 100	nA
I_{DSS}	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	250 1	μA mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 \cdot I_{D25}$	11N80 13N80 Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$	0.95 0.80	Ω Ω

IXYS reserves the right to change limits, test conditions, and dimensions.

91528F(7/97)

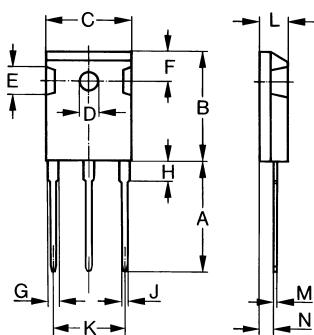
© 2000 IXYS All rights reserved

1 - 4

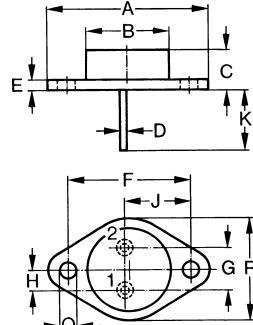
Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test	8	14	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	4200	pF	
		360	pF	
		100	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 2 \Omega$ (External)	20	50	ns
		33	50	ns
		63	100	ns
		32	50	ns
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	128	155	nC
		30	45	nC
		55	80	nC
R_{thJC}			0.42	K/W
R_{thCK}		0.25		K/W

Source-Drain Diode

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
I_s	$V_{GS} = 0 \text{ V}$	11N80 13N80		11 A 13 A
I_{SM}	Repetitive; pulse width limited by T_{JM}	11N80 13N80		44 A 52 A
V_{SD}	$I_F = I_S, V_{GS} = 0 \text{ V},$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = I_S$ $-di/dt = 100 \text{ A}/\mu\text{s}$, $V_R = 100 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	250 ns 400 ns	
			1	μC
			8.5	A

TO-247 AD (IXFH) Outline


Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102

TO-204 AA (IXFM) Outline


Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	38.61	39.12	1.520	1.540
B	19.43	19.94	-	0.785
C	6.40	9.14	0.252	0.360
D	0.97	1.09	0.038	0.043
E	1.53	2.92	0.060	0.115
F	30.15	BSC	1.187	BSC
G	10.67	11.17	0.420	0.440
H	5.21	5.71	0.205	0.225
J	16.64	17.14	0.655	0.675
K	11.18	12.19	0.440	0.480
Q	3.84	4.19	0.151	0.165
R	25.16	25.90	0.991	1.020

Fig. 1 Output Characteristics

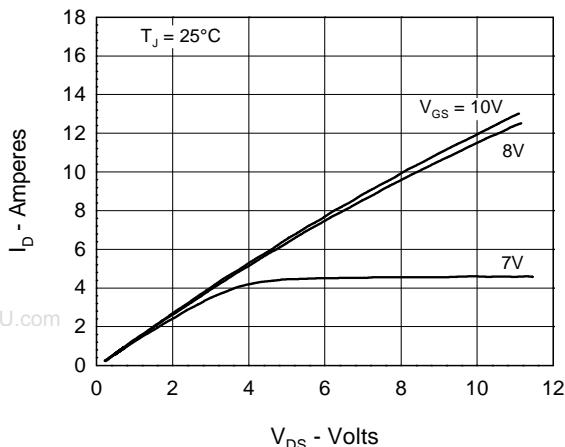


Fig. 3 $R_{DS(on)}$ vs. Drain Current

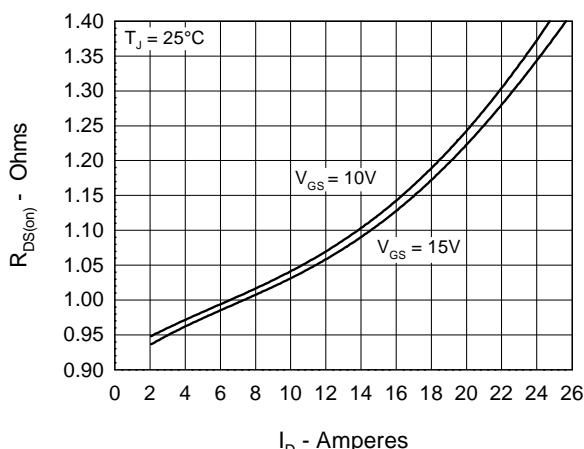


Fig. 5 Drain Current vs. Case Temperature

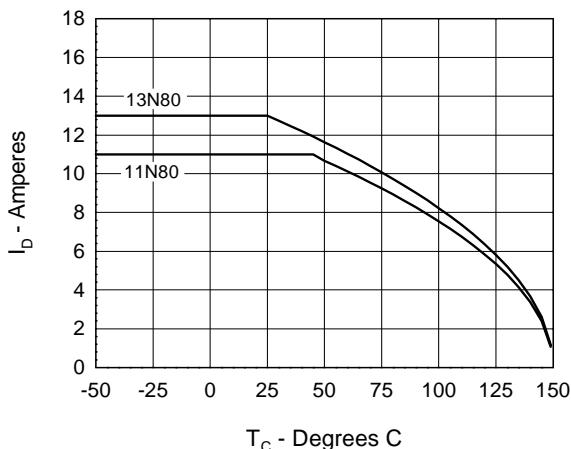


Fig. 2 Input Admittance

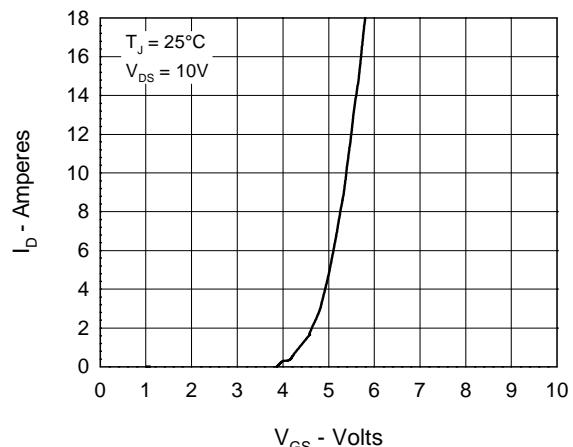


Fig. 4 Temperature Dependence of Drain to Source Resistance

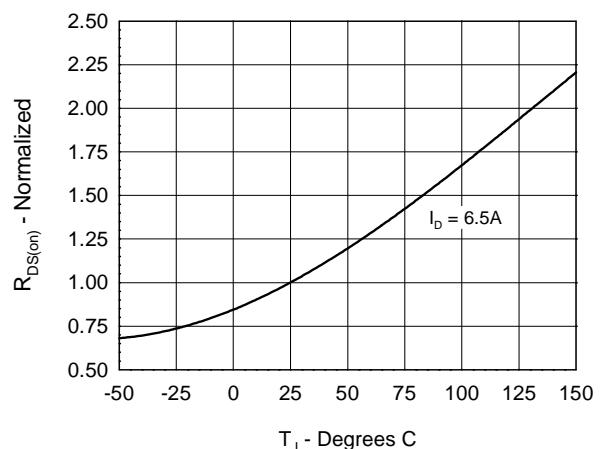


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage

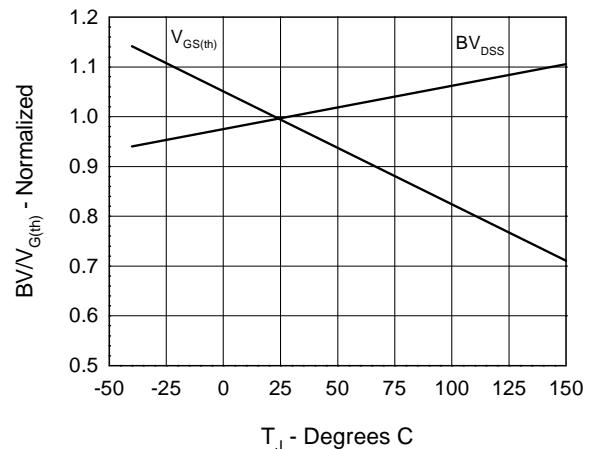


Fig.7 Gate Charge Characteristic Curve

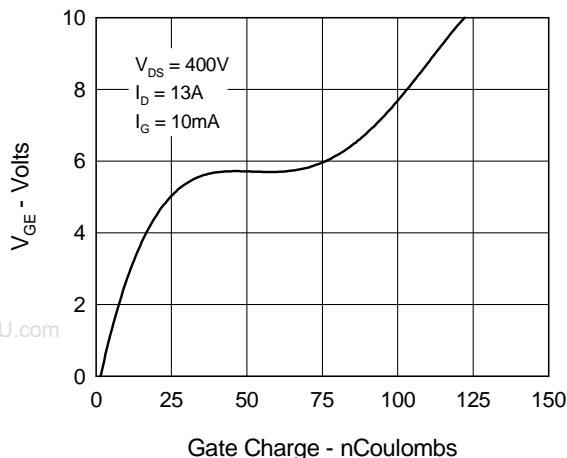


Fig.8 Forward Bias Safe Operating Area

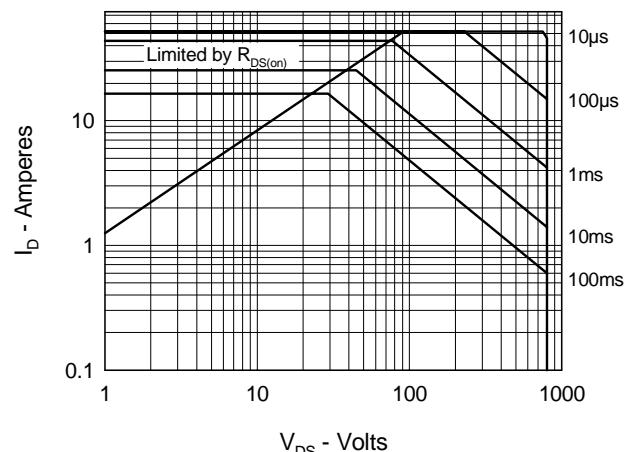


Fig.9 Capacitance Curves

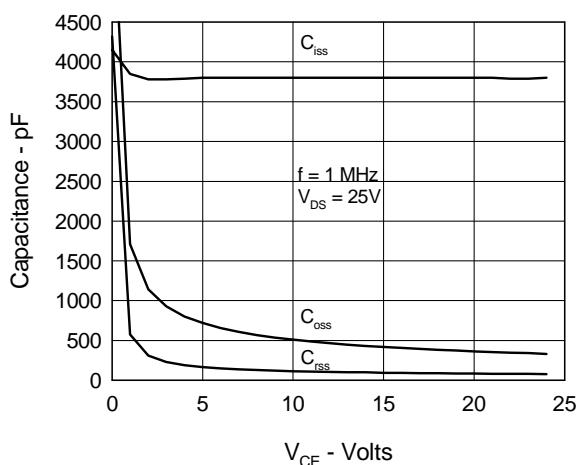


Fig.10 Source Current vs. Source to Drain Voltage

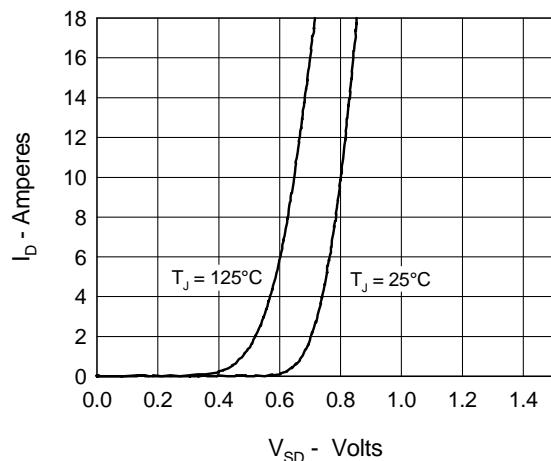


Fig.11 Transient Thermal Impedance

